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(54) **MEASUREMENT SYSTEM AND METHOD
FOR MEASURING AND ANALYZING
MODULATED SIGNALS**

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(57) **ABSTRACT**

The invention relates to a measurement system, including a signal analyzer or monitoring receiver, for measuring and analyzing modulated signals. The system includes a signal acquisition device having input port(s), wherein the signal acquisition device is configured to capture modulated signal (s) applied to the input ports, wherein each captured modulated signal can be represented as an I/Q signal; wherein the signal acquisition device generates at least two digital I/Q data streams based on the one or more modulated signals, wherein the at least two digital I/Q data streams are generated in parallel. The measurement system includes a selection device to select at least one target frequency bandwidth in each of the at least two digital I/Q data streams; and a signal processing device configured to analyze the at least two digital I/Q data streams in the selected target frequency bandwidths.

